

**Power Supply Characteristics**

Parameter	Description	Test Conditions	Typ. <sup>[5]</sup>	Max.	Unit
$I_{CC}$	Quiescent Power Supply Current	$V_{CC} = \text{Max.}, V_{IN} \leq 0.2V,$ $V_{IN} \geq V_{CC} - 0.2V$	0.1	0.2	mA
$\Delta I_{CC}$	Quiescent Power Supply Current (TTL inputs HIGH)	$V_{CC} = \text{Max.}, V_{IN} = 3.4V^{[8]}$ $f_1 = 0, \text{Outputs Open}$	0.5	2.0	mA
$I_{CCD}$	Dynamic Power Supply Current <sup>[9]</sup>	$V_{CC} = \text{Max.}, \text{One Bit Toggling},$ $50\% \text{ Duty Cycle, Outputs Open,}$ $MR = V_{CC},$ $V_{IN} \leq 0.2V \text{ or } V_{IN} \geq V_{CC} - 0.2V$	0.06	0.12	mA/ MHz
$I_C$	Total Power Supply Current <sup>[10]</sup>	$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz},$ $50\% \text{ Duty Cycle, Outputs Open,}$ $\text{One Bit Toggling at } f_1 = 5 \text{ MHz,}$ $MR = V_{CC},$ $V_{IN} \leq 0.2V \text{ or } V_{IN} \geq V_{CC} - 0.2V$	0.7	1.4	mA
		$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz},$ $50\% \text{ Duty Cycle, Outputs Open,}$ $\text{One Bit Toggling at } f_1 = 5 \text{ MHz,}$ $MR = V_{CC},$ $V_{IN} = 3.4V \text{ or } V_{IN} = \text{GND}$	1.2	3.4	mA
		$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz},$ $50\% \text{ Duty Cycle, Outputs Open,}$ $\text{Eight Bits Toggling at } f_1 = 2.5 \text{ MHz,}$ $MR = V_{CC},$ $V_{IN} \leq 0.2V \text{ or } V_{IN} \geq V_{CC} - 0.2V$	1.6	3.2 <sup>[11]</sup>	mA
		$V_{CC} = \text{Max.}, f_0 = 10 \text{ MHz}, 50\% \text{ Duty Cycle,}$ $\text{Outputs Open, Eight Bits Toggling at}$ $f_1 = 2.5 \text{ MHz,}$ $MR = V_{CC},$ $V_{IN} = 3.4V \text{ or } V_{IN} = \text{GND}$	3.9	12.2 <sup>[11]</sup>	mA

**Notes:**

8. Per TTL driven input ( $V_{IN} = 3.4V$ ); all other inputs at  $V_{CC}$  or GND.

9. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.

10.  $I_C = I_{CC} + \Delta I_{CC} D_{IH} N_I + I_{CCD} (f_0/2 + f_1 N_I)$   
 $I_C$  = Total Power Supply Current  
 $I_{CC}$  = Quiescent Current with CMOS input levels  
 $\Delta I_{CC}$  = Power Supply Current for a TTL HIGH input ( $V_{IN} = 3.4V$ )  
 $D_{IH}$  = Duty Cycle for TTL inputs HIGH

$N_I$  = Number of TTL inputs at  $D_{IH}$

$I_{CCD}$  = Dynamic Current caused by an input transition pair (HLH or LHL)

$f_0$  = Clock frequency for registered devices, otherwise zero

$f_1$  = Input signal frequency

$N_I$  = Number of inputs changing at  $f_1$

All currents are in milliamps and all frequencies are in megahertz.

11. Values for these conditions are examples of the  $I_{CC}$  formula. These limits are guaranteed but not tested.



**Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
5.8	CY74FCT273CTPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT273CTQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT273CTSOC	S5	20-Lead (300-Mil) Molded SOIC	
6.5	CY54FCT273CTDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT273CTLMB	L61	20-Square Leadless Chip Carrier	
7.2	CY74FCT273ATPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT273ATQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT273ATSOC	S5	20-Lead (300-Mil) Molded SOIC	
8.3	CY54FCT273ATDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT273ATLMB	L61	20-Square Leadless Chip Carrier	
13.0	CY74FCT273TPC	P5	20-Lead (300-Mil) Molded DIP	Commercial
	CY74FCT273TQC	Q5	20-Lead (150-Mil) QSOP	
	CY74FCT273TSOC	S5	20-Lead (300-Mil) Molded SOIC	
15.0	CY54FCT273TDMB	D6	20-Lead (300-Mil) CerDIP	Military
	CY54FCT273TLMB	L61	20-Square Leadless Chip Carrier	

Document #: 38-00380